

## Description

### N-channel Enhancement Mode Power MOSFET

#### Features

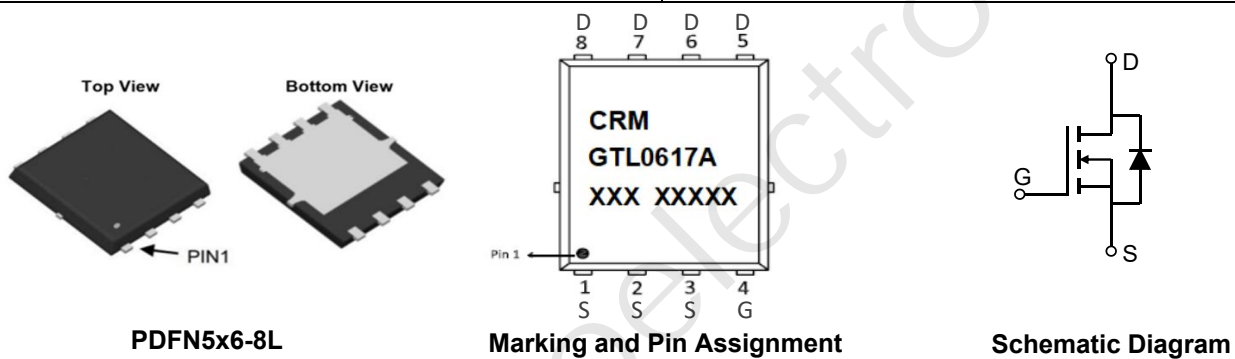
- 60V, 40A  
 $R_{DS(ON)}$  Typ= 12m $\Omega$  @  $V_{GS}$  = 10V  
 $R_{DS(ON)}$  Typ= 16m $\Omega$  @  $V_{GS}$  = 4.5V
- Advanced Trench Technology
- Excellent  $R_{DS(ON)}$  and Low Gate Charge

#### Applications

- Load Switch
- PWM Application
- Power Management



100% UIS TESTED!  
 100%  $\Delta V_{ds}$  TESTED!



### Package Marking and Ordering Information

Device Marking	Device	Outline	Package	Reel Size	Reel(pcs)	Per Carton (pcs)
CRMGTL0617A	CRMGTL0617A	TAPING	PDFN5x6-8L	13"	5000	50000

### Absolute Maximum Ratings (@ $T_C$ = 25°C unless otherwise specified)

Symbol	Parameter	Value	Units
$V_{DS}$	Drain-to-Source Voltage	60	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$I_D$	Continuous Drain Current	$T_C = 25^\circ\text{C}$	A
		$T_C = 100^\circ\text{C}$	
$I_{DM}$	Pulsed Drain Current <sup>(1)</sup>	160	A
$E_{AS}$	Single Pulsed Avalanche Energy <sup>(2)</sup>	72	mJ
$P_D$	Power Dissipation	$T_C = 25^\circ\text{C}$	W
$R_{\theta JC}$	Thermal Resistance, Junction to Ambient	3	$^\circ\text{C/W}$
$T_J, T_{STG}$	Junction & Storage Temperature Range	-55 to 150	$^\circ\text{C}$



## Electrical Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
V <sub>(BR)DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	60	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 60V, V <sub>GS</sub> = 0V	-	-	1.0	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
On Characteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1	1.5	2.2	V
R <sub>DS(ON)</sub>	Static Drain-Source ON-Resistance <sup>(3)</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 30A	-	12	15	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A	-	16	21	mΩ
Dynamic Characteristics						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 25V, f = 1MHz	-	2030	-	pF
C <sub>oss</sub>	Output Capacitance		-	133	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	122	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>GS</sub> = 0 to 10V V <sub>DS</sub> = 30V, I <sub>D</sub> = 30A	-	45	-	nC
Q <sub>gs</sub>	Gate Source Charge		-	8	-	nC
Q <sub>gd</sub>	Gate Drain("Miller") Charge		-	11	-	nC
Switching Characteristics						
t <sub>d(on)</sub>	Turn-On DelayTime	V <sub>GS</sub> = 10V, V <sub>DD</sub> = 30V I <sub>D</sub> = 30A, R <sub>GEN</sub> = 1.8Ω	-	11	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	79	-	ns
t <sub>d(off)</sub>	Turn-Off DelayTime		-	33	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	107	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	40	A
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	160	A
V <sub>SD</sub>	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 30A	-	-	1.2	V

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
  2.  $E_{AS}$  condition: Starting  $T_J = 25^\circ\text{C}$ ,  $V_{DD} = 30\text{V}$ ,  $V_G = 10\text{V}$ ,  $R_G = 25\Omega$ ,  $L = 0.5\text{mH}$ ,  $I_{AS} = 17\text{A}$
  3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$ .

## Typical Performance Characteristics

Figure 1: Output Characteristics

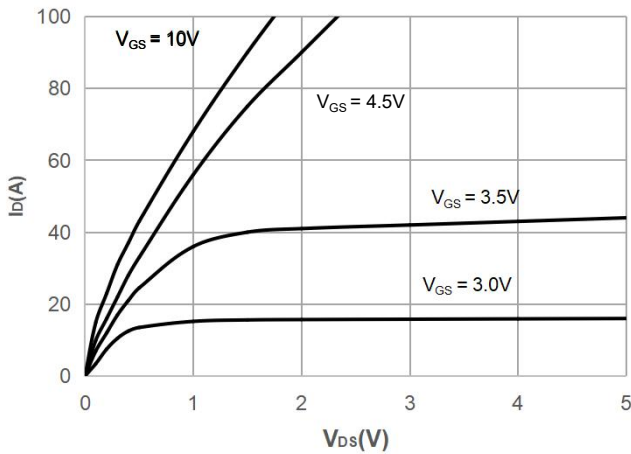


Figure 2: Typical Transfer Characteristics

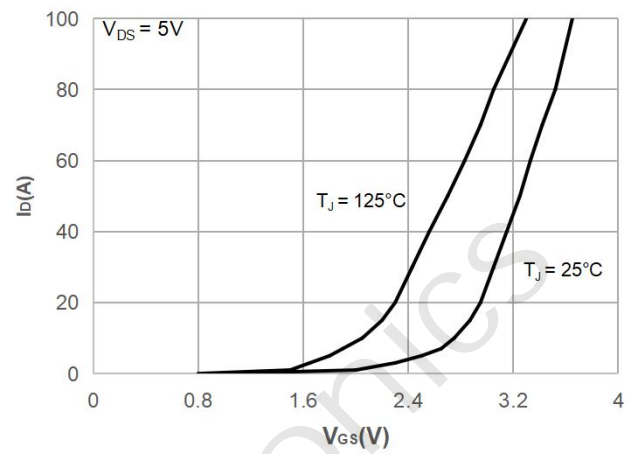


Figure 3: On-resistance vs. Drain Current

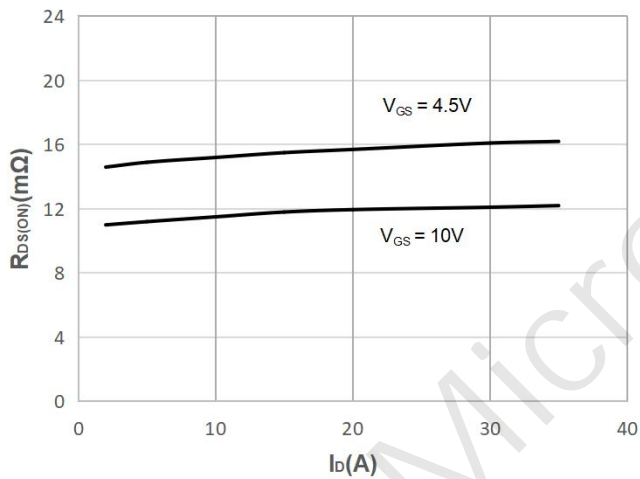


Figure 4: Body Diode Characteristics

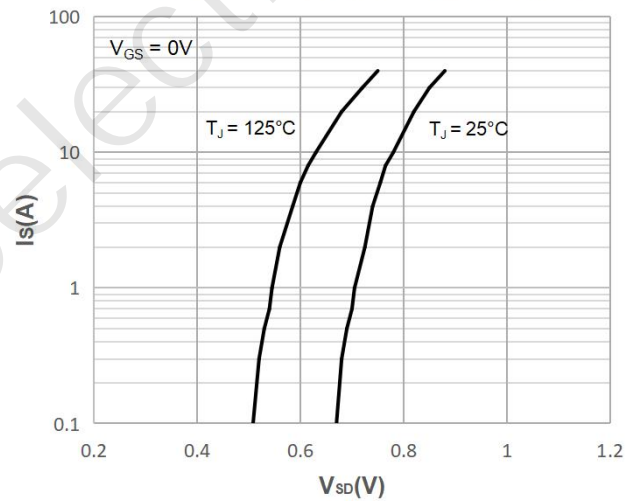


Figure 5: Gate Charge Characteristics

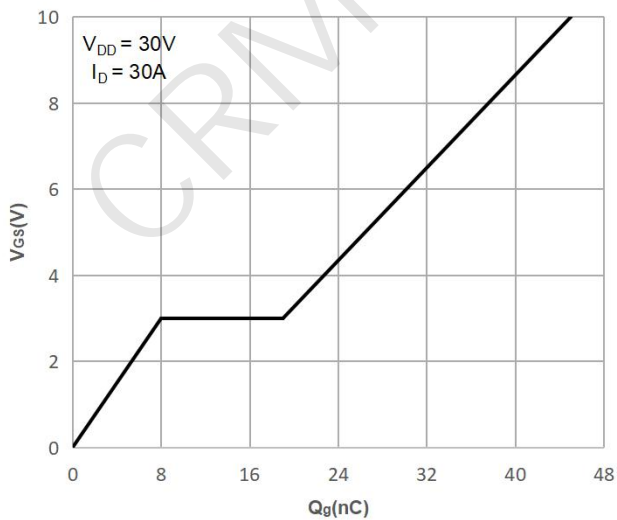
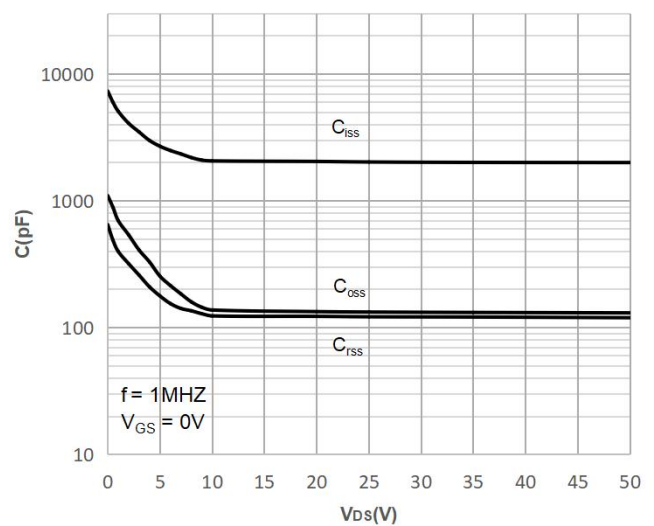


Figure 6: Capacitance Characteristics



## Typical Performance Characteristics

Figure 7: Normalized Breakdown voltage vs. Junction Temperature

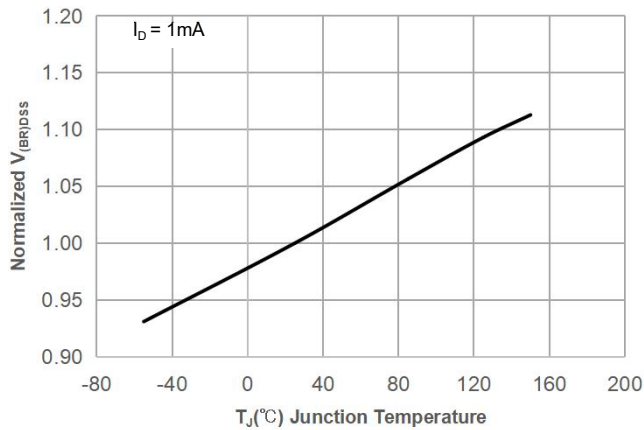


Figure 8: Normalized on Resistance vs. Junction Temperature

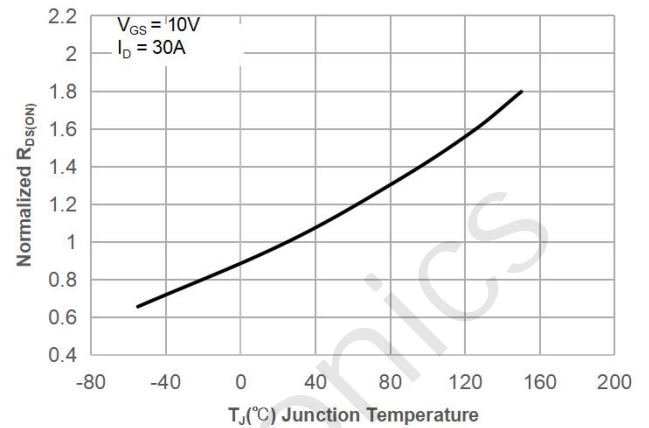


Figure 9: Maximum Safe Operating Area

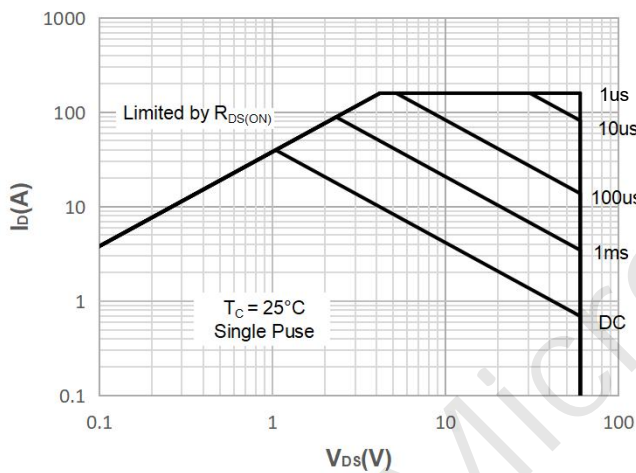


Figure 10: Maximum Continuous Drian Current vs. Case Temperature

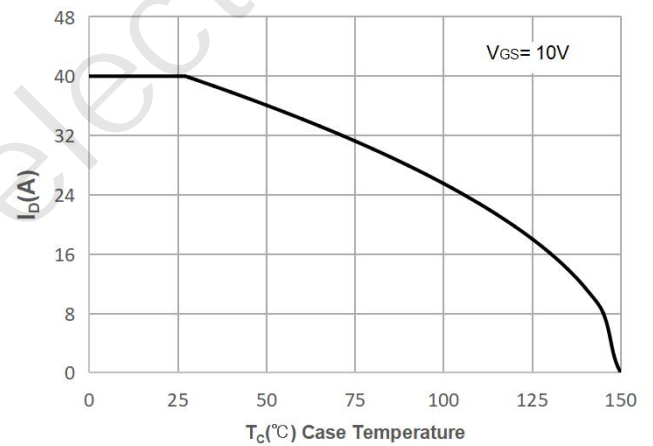


Figure 11: Normalized Maximum Transient Thermal Impedance

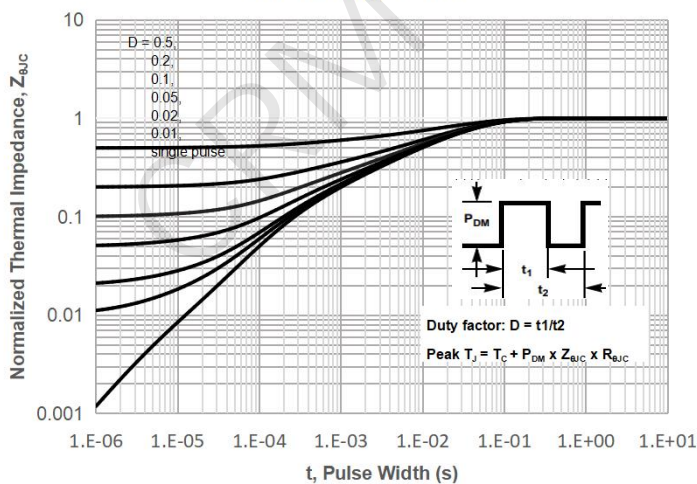
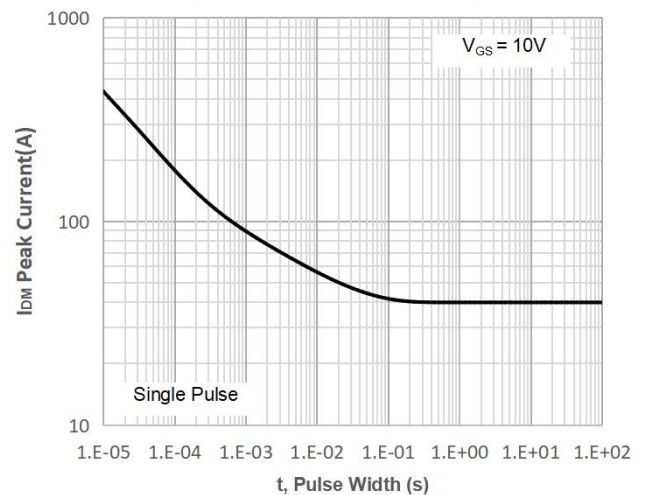


Figure 12: Peak Current Capacity



## Test Circuit

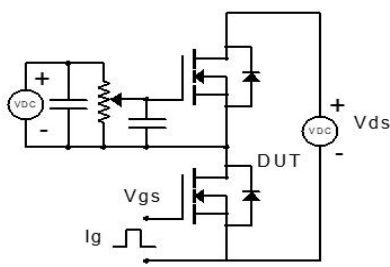


Figure 1: Gate Charge Test Circuit & Waveform

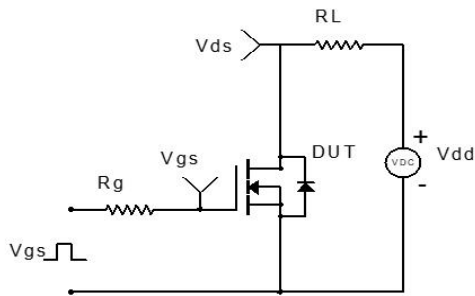


Figure 2: Resistive Switching Test Circuit & Waveform

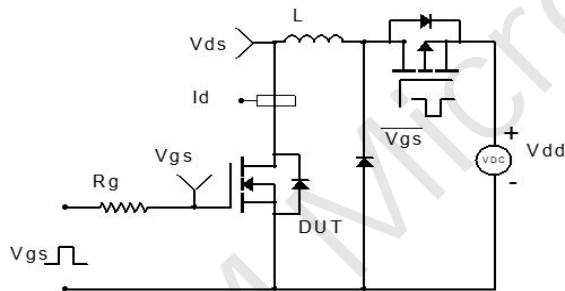


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

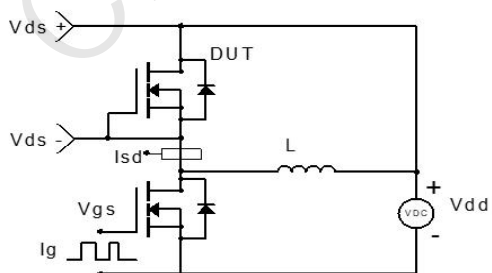
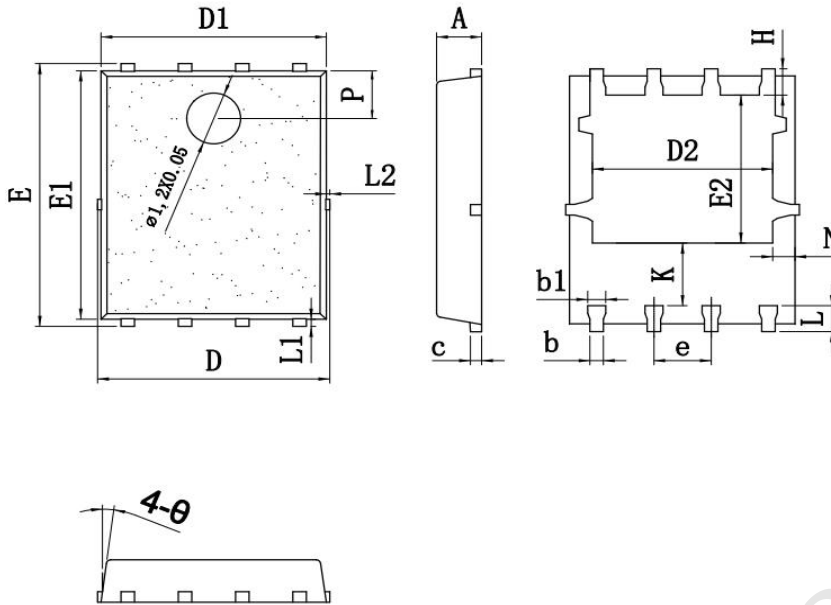


Figure 4: Diode Recovery Test Circuit & Waveform

## Package Mechanical Data(PDFN5X6-8L)




SYMBOL	mm		
	MIN	NOM	MAX
*A	0.95	1.00	1.05
*b	0.25	0.30	0.35
*b1	0.30	0.40	0.50
*c	0.20	0.25	0.30
D	5.15BSC		
*D1	4.90	5.00	5.10
D2	3.90	4.01	4.20
*e	1.17	1.27	1.37
E	6.15BSC		
*E1	5.75	5.85	5.95
E2	3.35	3.50	3.65
H	0.51	0.61	0.71
K	1.10	1.35	1.50
L	0.51	0.61	0.71
L1	0.06	0.13	0.20
L2	-	-	0.12
N	0.40	0.50	0.60
P	0.95	1.10	1.25
θ	9°	11°	13°

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